# Data Push and Data Mining in the Age of Artificial Intelligence

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Deadline for manuscript submissions:
**closed (15 April 2024)**

## Message from the Guest Editor

Dear Colleagues,

Artificial Intelligence (AI) is one of the ultimate goal of computers. AI can passively obtain knowledge and rules from data mining technology, and also can actively push data, alarm, remind, or even make the decision from user's devices when some criterion is fulfilled. Recently, big data collecting from IoT, stock, healthcare, automobile vision, and so on. Streaming data as well as its auto control is a mature technology. The intervention of A.I. plays the role of solving the most tedious and timely problems.

The aim of this Special Issue is to focus on the "data push and data mining of the age of artificial intelligence", providing new approaches and technologies for better understanding knowledge-based artificial intelligence. Submissions to this Special Issue are solicited to represent an innovative and creative snapshot of the field's development by covering a range of topics that include but are not limited to: data push; data mining (such as association rule, time sequence, outlier, etc.); knowledge representation; topology; AI algorithms, solutions, and applications.

We look forward to receiving your contributions.

**Special**Issue

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## Message from the Editor-in-Chief

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